

ShanghaiTech University
School of Information Science and Technology

EE112 Lab Experiments

**Experiment 2: Diodes, Bipolar Junction Transistors
and MOS Characterization**

3. Pre-Lab

3.1 Junction capacitance

V is the dc applied voltage across diode. The junction may be forward biased ($V > 0$), or reverse biased ($V < 0$).

$V=0$, C_j : _____

$V=-5$ V, C_j : _____

$V=-10$ V, C_j : _____

3.2 I-V measurement of NMOS

Show the Labview program which can be used to measure the I-V curve of NMOS in Elvis II to TAs.